


<b>Search Notes</b>  	<b>Application/Control No.</b>  10637199	<b>Applicant(s)/Patent Under Reexamination</b>  TYAN ET AL.
	<b>Examiner</b>  RYAN LEPISTO	<b>Art Unit</b>  2883

SEARCHED			
Class	Subclass	Date	Examiner
385	45	8/22/08	RAL

SEARCH NOTES		
Search Notes	Date	Examiner
See search history - EAST (all databases), non-patent literature (IEEE, OpticsInfoBase)	8/22/08	RAL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
385	45	8/22/08	RAL

--	--